

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/719,484 CHEN ET AL.	
		Examiner	Art Unit	Page 1 of 1 David E. Martinez 2181

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0103210 A1	05-2004	Fujii et al.	709/239
*	B	US-2005/0063334 A1	03-2005	Fnu et al.	370/329
*	C	US-6,937,611 B1	08-2005	Ward, Kenneth A.	370/462
*	D	US-6,996,629 B1	02-2006	Odenwald, Louis	709/238
*	E	US-2001/0025308 A1	09-2001	Jinushi et al.	709/219
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.